

EE2019

N : # bits,

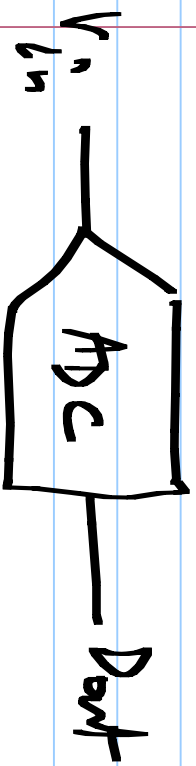
V_{ref} : reference voltage

f_s : sampling rate

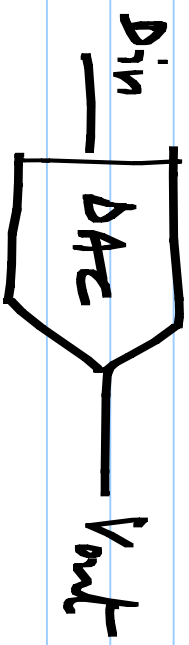
20/4/2018

Analogue-to-Digital conversion Digital-to-Analogue

(ADCs)



(DACs)



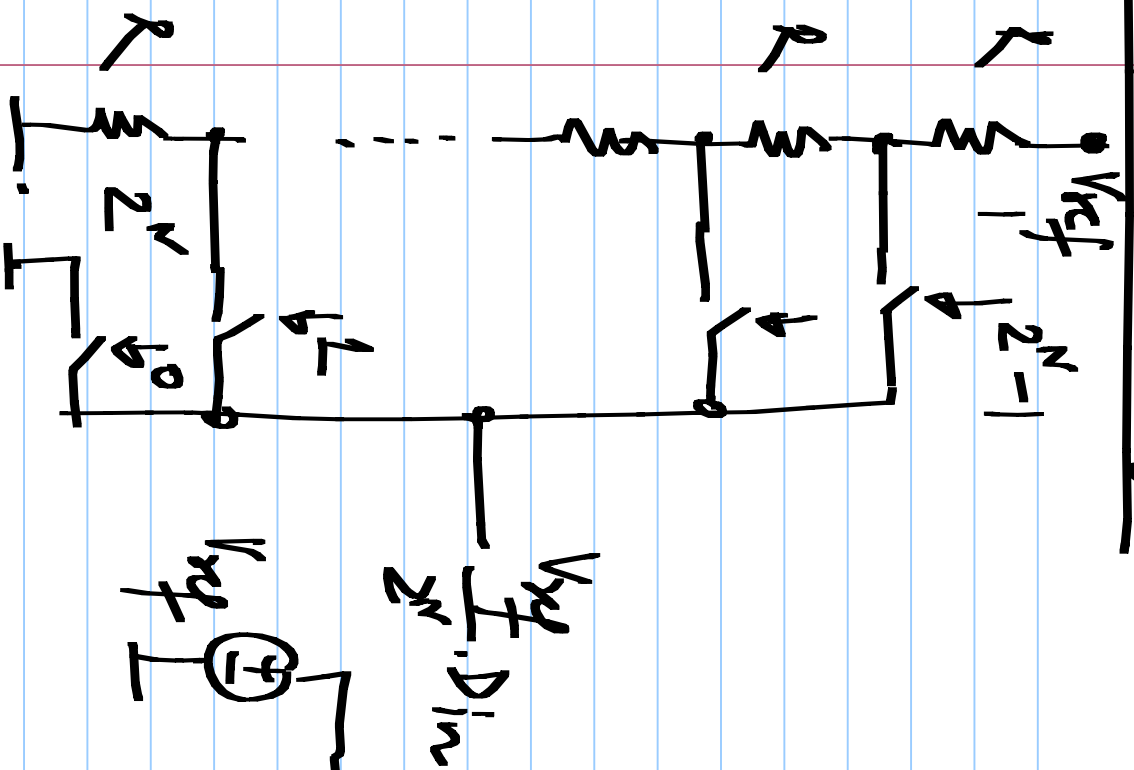
$D_{out} = k$ if

$$\frac{V_{ref}}{2^N} \cdot k < V_{in} \leq \frac{V_{ref}}{2^N} \cdot k + 1$$

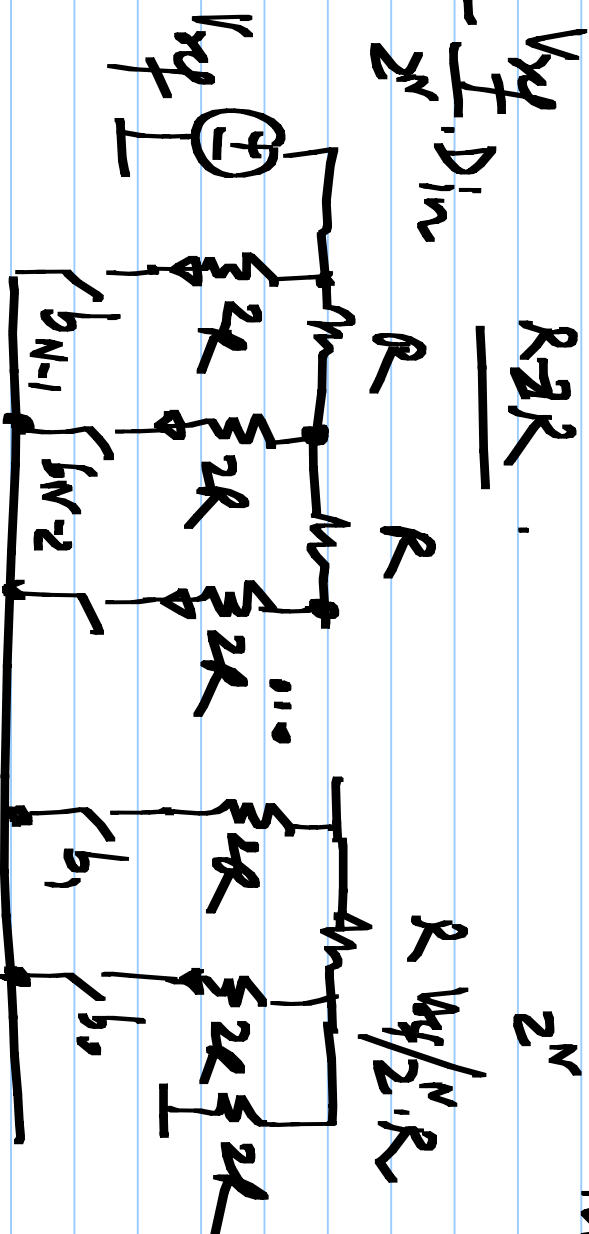
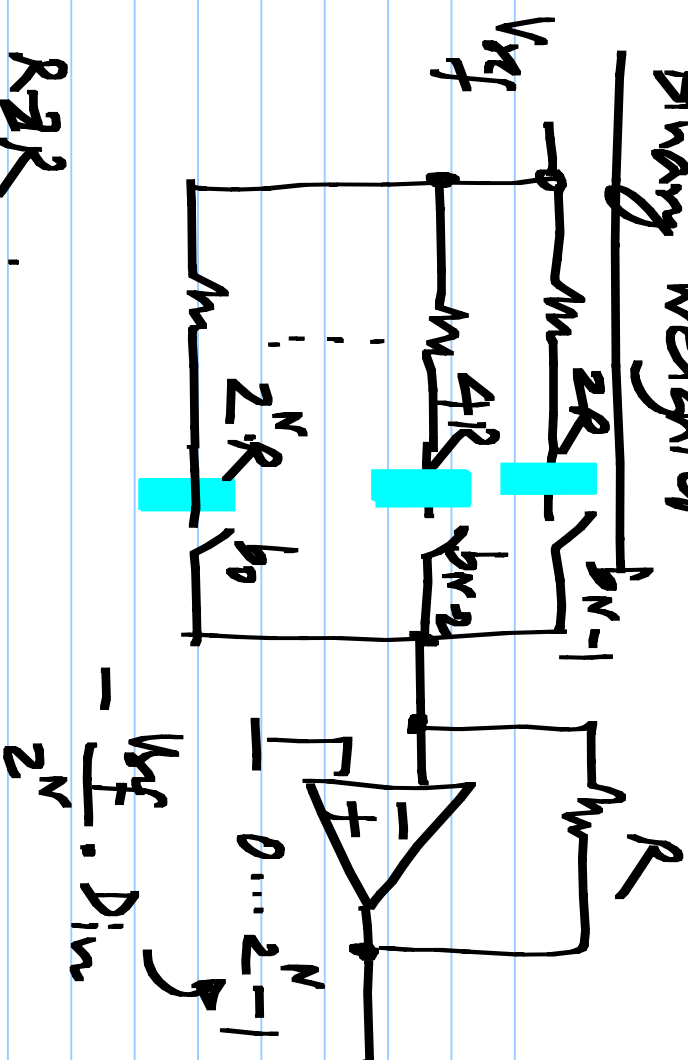
$$V_{out} = D_{in} \cdot \frac{V_{ref}}{2^N}$$

N : # bits

Resistor-string



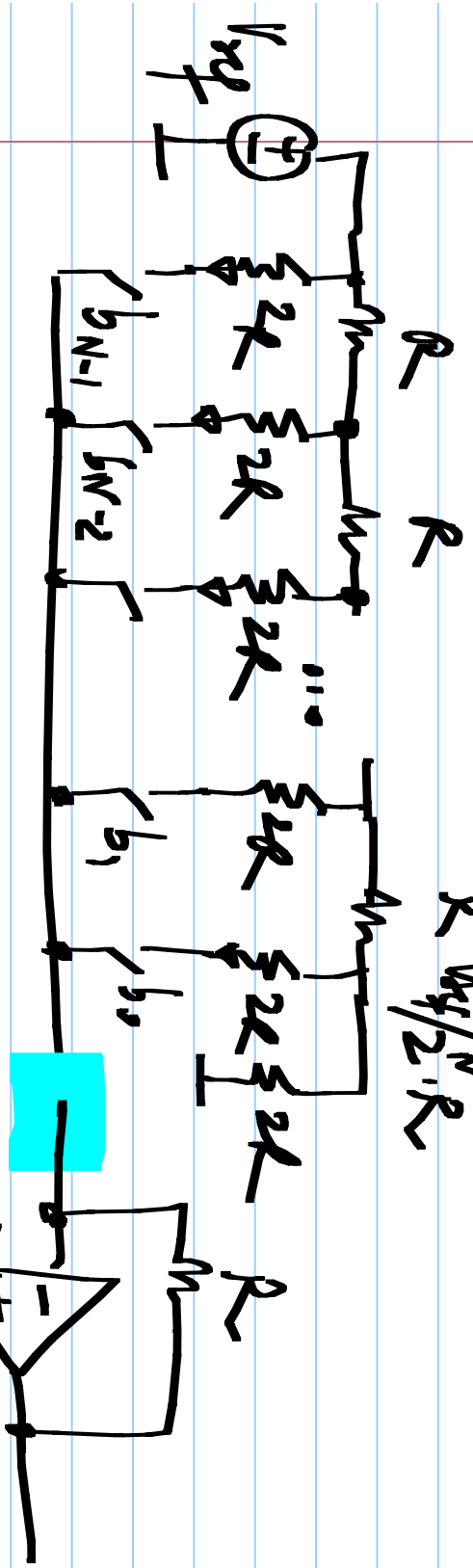
Binary weighted



$$\frac{R \cdot 2R}{R + 2R}$$

$$2^N$$

$$2 \cdot \frac{V_{ref}}{2^N} \cdot R$$

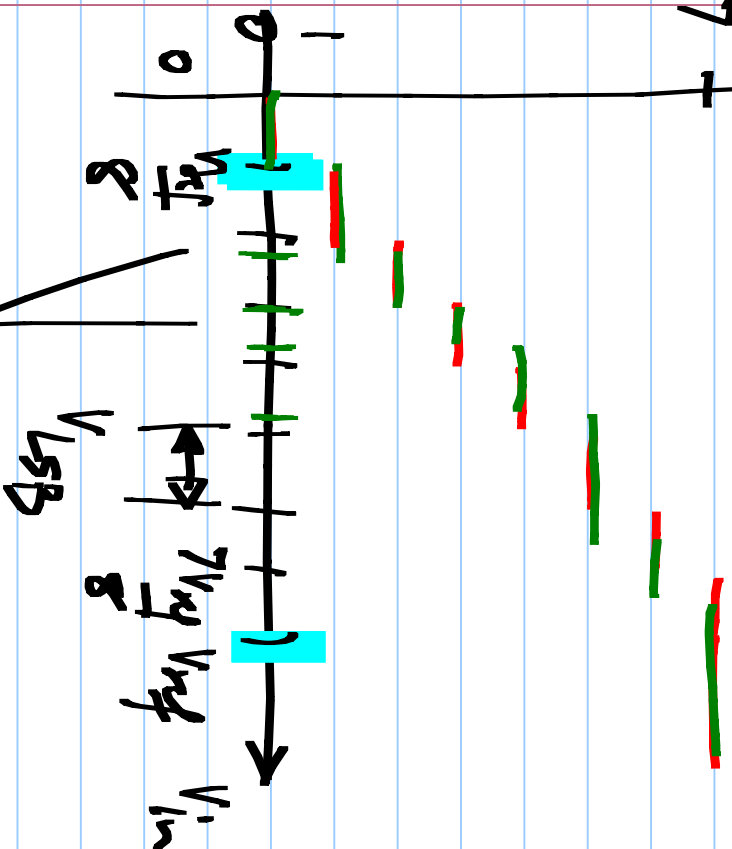


$$V_{out} = \frac{V_{ref}}{2^N} \cdot D_{in}$$

$$D_{in} : b_{N-1} b_{N-2} \dots b_1 b_0$$

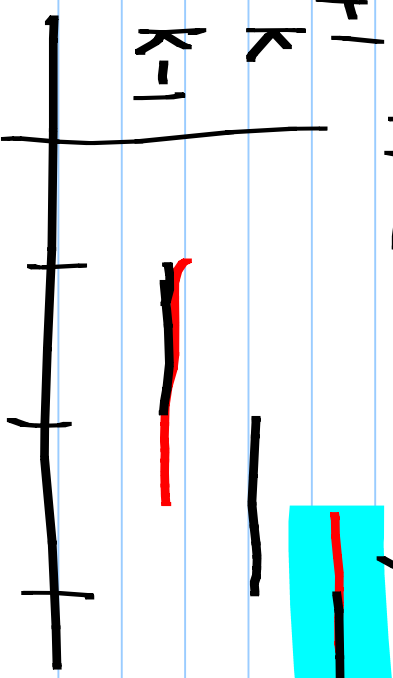
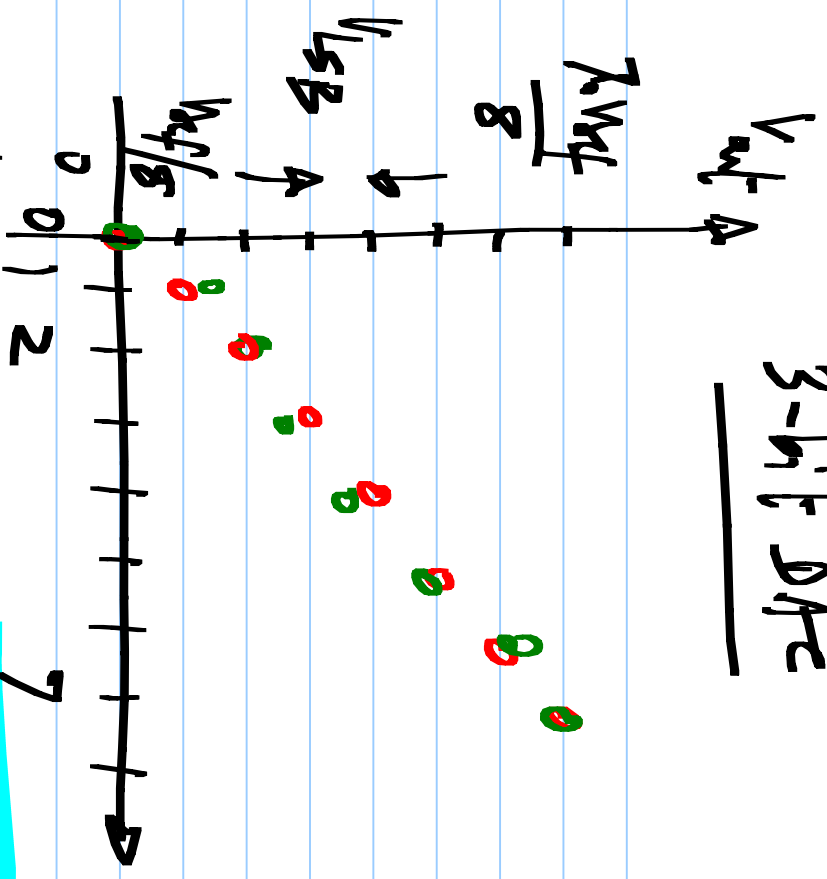
3-bit ADC

Def A



Transition points define the ADC

3-bit DAC



ADC
All transition levels move by V_{off} } offset error
All DAC output levels move by V_{off}

Equally sized steps, but different from $\frac{V_{\text{ref}}}{2^N} \neq V_{\text{LSB}}$

Different
ref. value $V'_{\text{ref}} = V_{\text{LSB}} \cdot 2^N$ } Gain error
(V_{ref} : intended ref. voltage)

Nonlinearity of ADCs & DACs

(Assume first & last values = ideal values) ^{their}
ADC transition levels: $\overline{V_{\text{AC}}[k]} \neq \frac{V_{\text{ref}}}{2^N} \cdot k$

output changes from $k-1$ to k if V_{in} crosses $V_{\text{AC}}[k]$

Integral nonlinearity error: $V_{\text{AC}}[k] - \frac{V_{\text{ref}}}{2^N} \cdot k$

(INL)

$V_{\text{ref}}/2^N$

If $\text{INL} < 1/2 \text{ LSB}$, no missing steps

$$\text{DNL}[k] \quad \text{DNL}[k] \quad \text{DNL}[k] \\ \text{Differential nonlinearity error} = \frac{V_{DC}[k] - V_{DC}[k-1] - \frac{V_{ref}}{2^N}}{\frac{V_{ref}}{2^N}} - \frac{V_{ref}}{2^N}$$

If $\text{DNL}[k] \leq 0.5 \text{ LSB}$ for all k , no missing steps

$$\text{INL}[k] = \frac{V_{DC}[k] - \frac{V_{ref}}{2^N} k}{\frac{V_{ref}}{2^N}}$$

Static errors

$$\text{DNL}[k] = \frac{\text{INL}[k] - \text{INL}[k-1]}{\frac{V_{ref}}{2^N}}$$

